

Search Notes

Application/Control No.

10/541,517

Examiner

HIEU T. VO

Applicant(s)/Patent under
Reexamination

TORNO ET AL.

Art Unit

3747

SEARCHED

Class	Subclass	Date	Examiner
701	111 110 114	11/22/2008	/HV/
123	406.21	11/22/2008	/HV/
123	406.35	11/22/2008	/HV/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/22/2008	/HV/